

**Notice of References Cited**

Application/Control No.

10/044,401

Applicant(s)/Patent Under  
Reexamination  
DELANO, ERIC R.

Examiner

Christopher E. Lee

Art Unit

2112

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,411,230 B1	06-2002	Tauchen et al.	341/101
	B	US-6,570,876 B1	05-2003	Aimoto, Takeshi	370/389
	C	US-6,363,452 B1	03-2002	Lach, Jorge E.	710/316
	D	US-6,249,528 B1	06-2001	Kothary, Piyush	370/466
	E	US-2002/0186656 A1	12-2002	Vu, Chuong D.	370/229
	F	US-6,324,613 B1	11-2001	Aguilar et al.	710/316
	G	US-5,941,941 A	08-1999	Hasegawa, Satoshi	708/551
	H	US-5,313,586 A	05-1994	Rutman, Serge	712/34
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 11265341 A	09-1999	Japan	HIRATA, AKIRA	G06F 13/36
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.